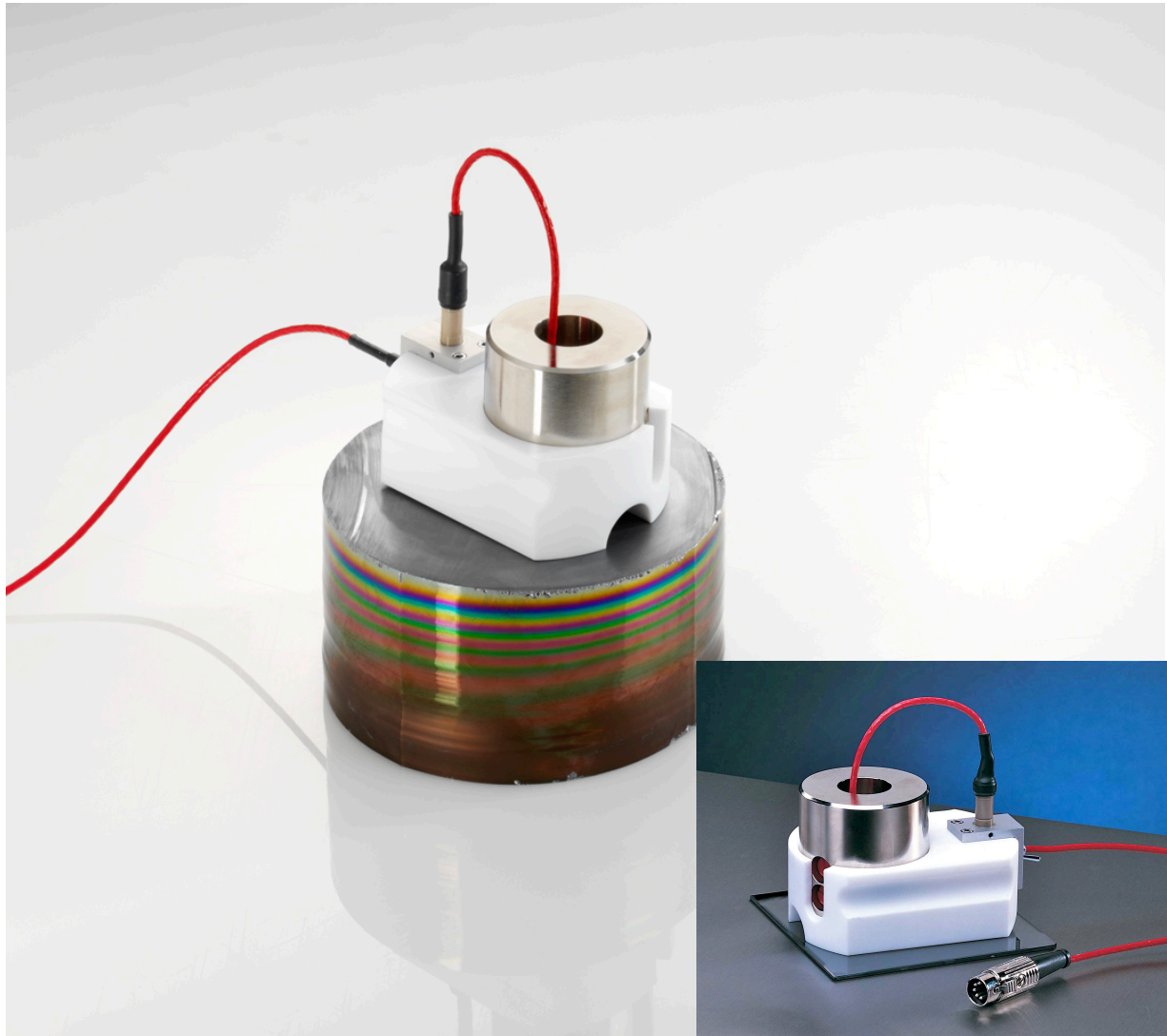


# Jandel Engineering Limited



## Jandel Hand Applied Probe

*Jandel Engineering Limited* offers the Hand Applied Probe as a solution for making measurements where portability is a key factor. The system can be used for measuring a wide variety of samples from thin layers and wafers up to large ingots. The probe head can have loads of up to 200g per needle and the Hand Applied Probe has a large downward force of around 1.2Kg and so is not suitable for fragile unsupported samples. As a scale for size the main image above shows the Hand Applied Probe sitting on top of a 150mm silicon ingot.

<i>Max. sample size</i>	Any reasonable size sample can be measured as long as the Hand Applied Probe can be placed appropriately
<i>Max. sample thickness</i>	Any thickness of sample can be measured as long as the Hand Applied Probe can be placed appropriately
<i>Toggle Switch</i>	Prevents current flow when probe is not in contact with the sample
<i>Manual Placement</i>	Probe is designed to be placed and left while measurement is made to avoid fluctuation associated with hand held measurement
<i>Simple set up</i>	Single wire connects the Hand Applied Probe and measurement electronics

Type	Tip R	Force	Spacing
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591mm
F	40u	100g	0.635mm
G	100u	100g	0.635mm
H	200u	100g	0.635mm

*Type A-D and F-H are user adjustable in the range 60g-150g and supplied at value shown*



*If you require any further information on the Jandel Hand Applied Probe please contact us using the details below*

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